

Notice of References Cited	Application/Control No. 10/769,240		Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner AMAL ZENATI		Art Unit 2614	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,798,876 B1	09-2004	Bala, Srinivas	379/265.12
*	C	US-4,896,358	01-1990	Bahler et al.	704/257
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.